

## AMGR45N1200MD02 1200V N-Channel MOSFET Gen2

### Description

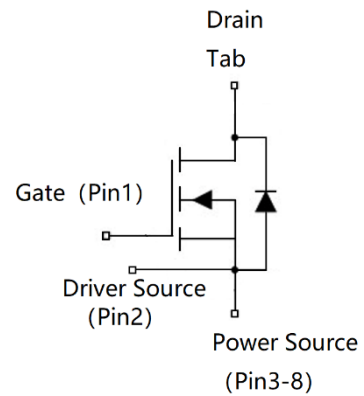
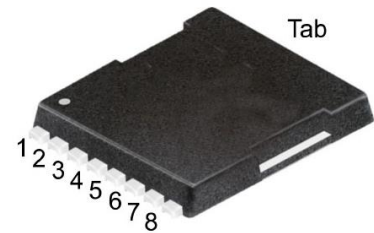
Silicon Carbide (SiC) MOSFET use a completely new technology that provide superior switching performance and higher reliability compared to Silicon. In addition, the low ON resistance and compact chip size ensure low capacitance and gate charge. Consequently, system benefits include highest efficiency, faster operating frequency, increased power density, reduced EMI, and reduced system size.

### Features

- High Speed Switching with Low Capacitances
- High Blocking Voltage with Low RDS(on)
- Optimized package with separate driver source pin
- Easy to parallel and simple to drive
- ROHS Compliant, Halogen free

### Application

- EV motor drive
- High Voltage DC/DC Converters
- Switch Mode Power Supplies
- Solar inverters
- EV charging



### Ordering Information

Part Number	Marking	Package	Packaging
AMGR45N1200MD02	AMGR45N1200MD02	Toll	Reel

**Absolute Maximum Ratings(Tc=25°C)**

Symbol	Parameter	Value	Unit
V <sub>DS</sub>	Drain-Source Voltage	1200	V
I <sub>D</sub>	Drain Current(continuous)at Tc=25°C	60	A
I <sub>D</sub>	Drain Current(continuous)at Tc=100°C	48	A
I <sub>DM</sub>	Drain Current (pulsed)	100	A
V <sub>GS</sub>	Gate-Source Voltage	-10/+22	V
P <sub>D</sub>	Power Dissipation T <sub>C</sub> = 25°C	218	W
T <sub>J</sub> , T <sub>stg</sub>	Junction and Storage Temperature Range	-55 to +175	°C

**Electrical Characteristics(T<sub>J</sub> = 25°C unless otherwise specified)**
**Typical Performance-Static**

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
BV <sub>DS</sub>	Drain-source Breakdown Voltage	I <sub>D</sub> =250uA, V <sub>GS</sub> =0V	1200			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =1200V, V <sub>GS</sub> =0V, T <sub>J</sub> =25°C			100	uA
I <sub>GSS</sub>	Gate-body Leakage Current	V <sub>DS</sub> =0V ; V <sub>GS</sub> =-10 to 20V			250	nA
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> =10mA	2	3	4	V
V <sub>GSon</sub>	Recommended turn-on Voltage	Static		18		V
V <sub>GSoff</sub>	Recommended turn-off Voltage			-5		V
R <sub>DS(on)</sub>	Static Drain-source On Resistance	V <sub>GS</sub> =18V, I <sub>D</sub> =20A		45	52	mΩ
		V <sub>GS</sub> =18V, I <sub>D</sub> =20A T <sub>J</sub> =175°C		81		mΩ

**Typical Performance-Dynamic**

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$C_{iss}$	Input Capacitance	$V_{DS}=1000V, f=100KHz,$ $V_{AC}=25mV$		2565		pF
$C_{oss}$	Output Capacitance			109		pF
$C_{riss}$	Reverse Transfer Capacitance			4		pF
$g_{fs}$	Transconductance	$V_{DS}=20V, I_D=20A$		24		S
$E_{OSS}$	$C_{OSS}$ Stored Energy	$V_{DS}=1000V, f=100KHz$		63		$\mu J$
$E_{ON}$	Turn-On Energy (Body Diode)	$V_{DS}=800V, V_{GS}=-5/20V,$ $I_D=30A, L=100\mu H$ $T_J=175^\circ C$		556		$\mu J$
$E_{OFF}$	Turn-Off Energy (Body Diode)			93		$\mu J$
$Q_g$	Total Gate Charge	$V_{DS}=800V, V_{GS}=-5V/20V,$ $I_D = 20A$		125		nC
$Q_{gs}$	Gate-source Charge			32		nC
$Q_{gd}$	Gate-Drain Charge			33		nC
$R_{G(int)}$	Internal Gate Resistance	$f=1MHz, V_{AC}=25mV$		4.2		$\Omega$
$t_{d(on)}$	Turn-on Delay Time	$V_{DS}=800V, V_{GS}=-5V/20V,$ $I_D = 20A, L=100 \mu H$ $R_{ext}=2.5\Omega$		13		ns
$t_r$	Rise Time			17		ns
$t_{d(off)}$	Turn-off Delay Time			23		ns
$t_f$	Fall Time			9		ns

**Typical Performance-Reverse Diode( $T_J = 25^\circ C$  unless otherwise specified)**

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$V_{FSD}$	Forward Voltage	$V_{GS}=0V, I_F=20A, T_J=25^\circ C$		4.2	6	V
		$V_{GS}=0V, I_F=20A, T_J=175^\circ C$		3.5	6	V
$I_S$	Continuous Diode Forward Current	$V_{GS}=0V, T_C=25^\circ C$		55		A
$t_{rr}$	Reverse Recovery Time	$V_{GS}=-5V, I_F=20A,$ $V_R=800V, di/dt=900$ $A/\mu s, T_J=175^\circ C$		50		nS
$Q_{rr}$	Reverse Recovery Charge			712		nC
$I_{rrm}$	Peak Reverse Recovery Current			19		A

**Thermal Characteristics**

Symbol	Parameter	Value.	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.69	$^\circ C/W$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62	$^\circ C/W$

The values are based on the junction-to case thermal impedance which is measured with the device mounted to a large heat sink assuming maximum junction temperature of  $T_J(max)=175^\circ C$

Electrical Characteristics

Fig1. Output characteristics ( $T_J = 25\text{ }^\circ\text{C}$ )

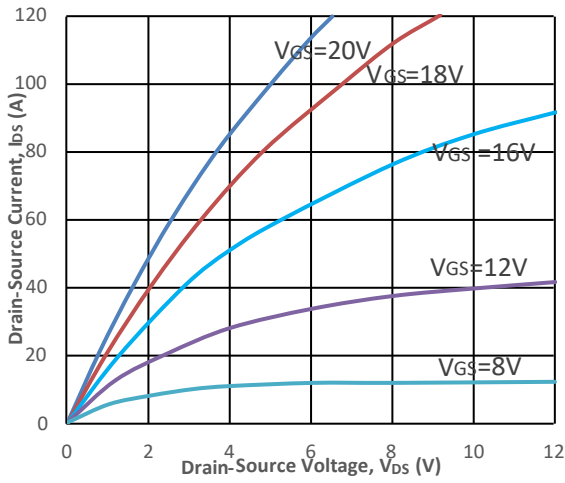


Fig2. Output characteristics ( $T_J = 175\text{ }^\circ\text{C}$ )

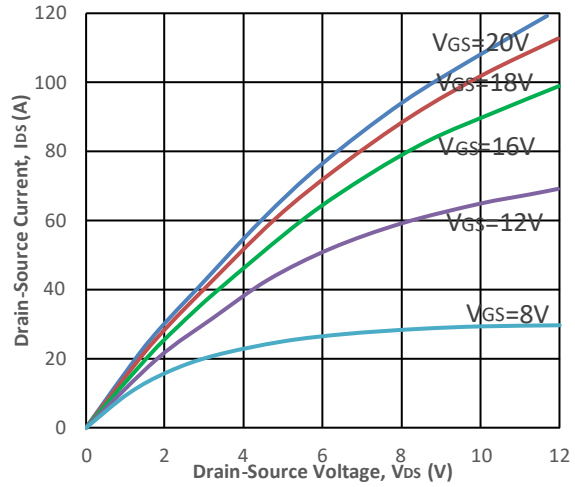


Fig3. Normalized On-Resistance vs. Temperature

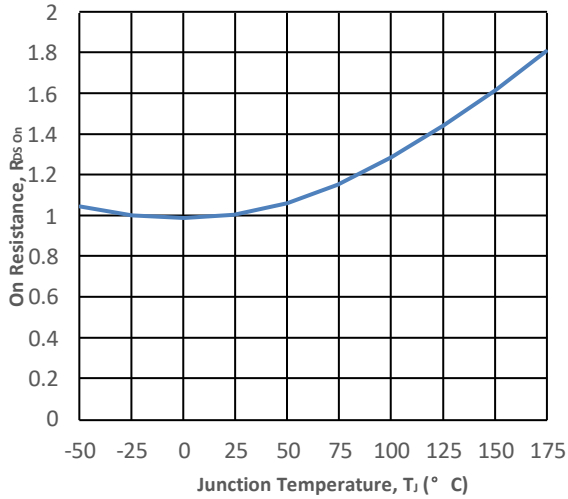


Fig4. On-Resistance vs. Temperature

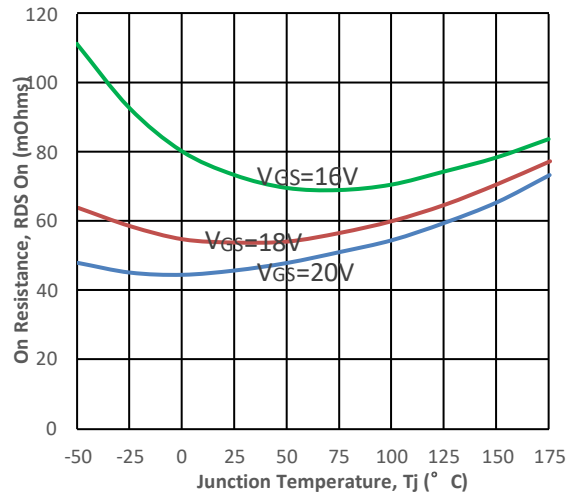


Fig5. Transfer Characteristic

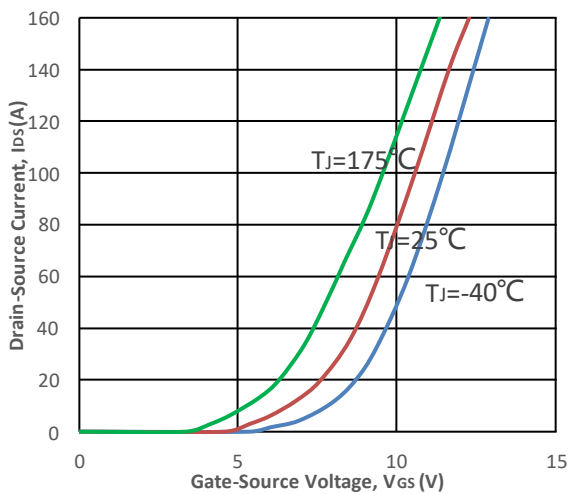
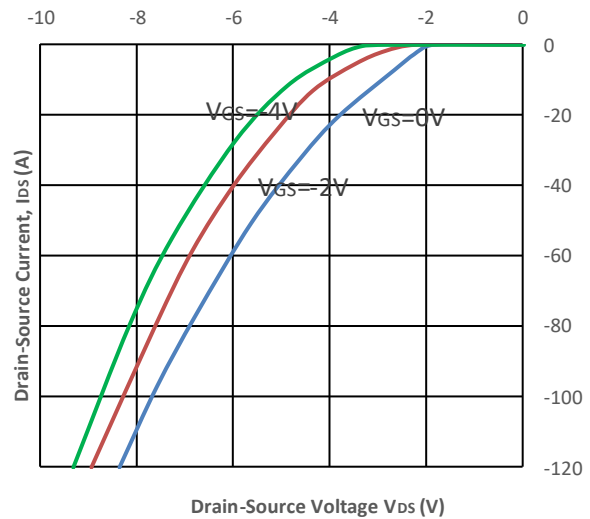
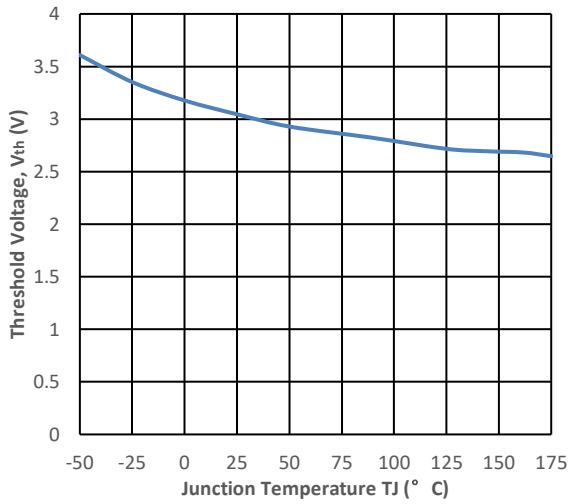


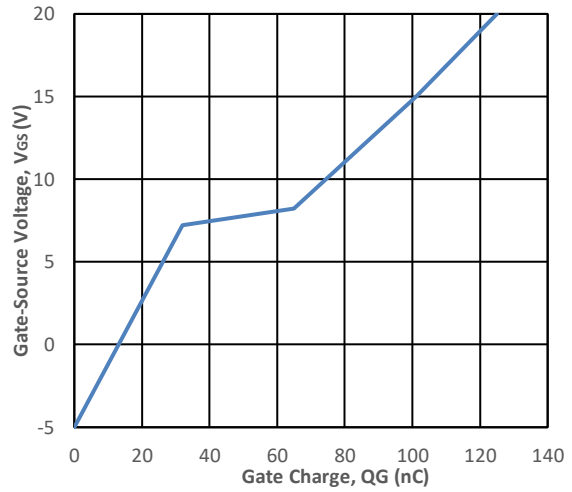
Fig6. Body Diode Characteristic at 25 °C



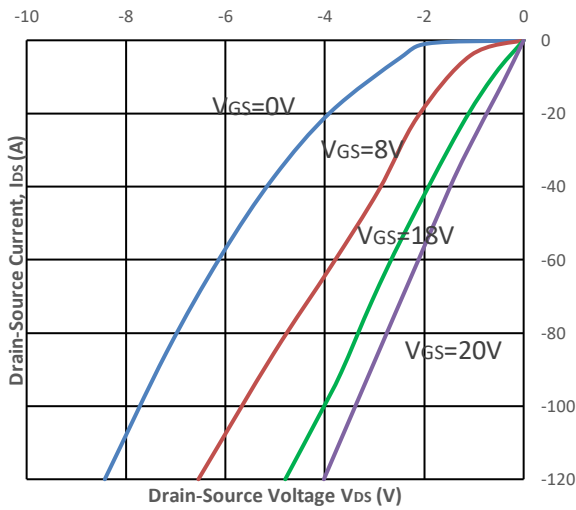
**Fig7. Threshold Voltage vs. Temperature**



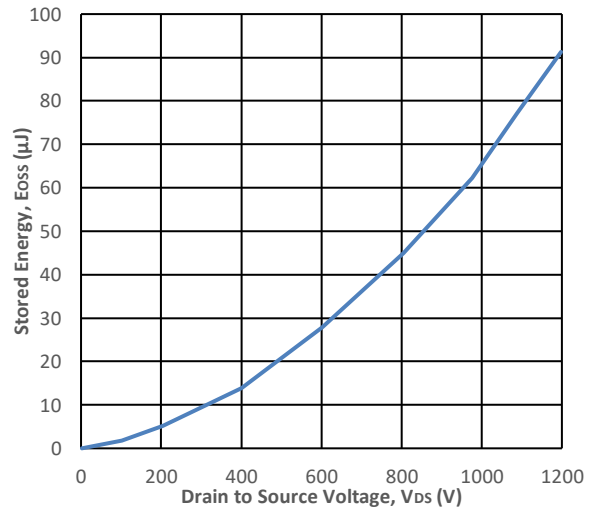
**Fig8. Gate Charge Characteristics**



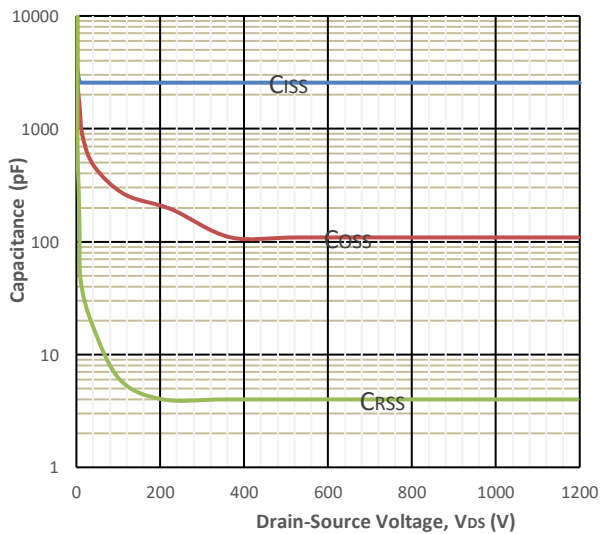
**Fig9. 3rd Quadrant Characteristic at 25 °C**



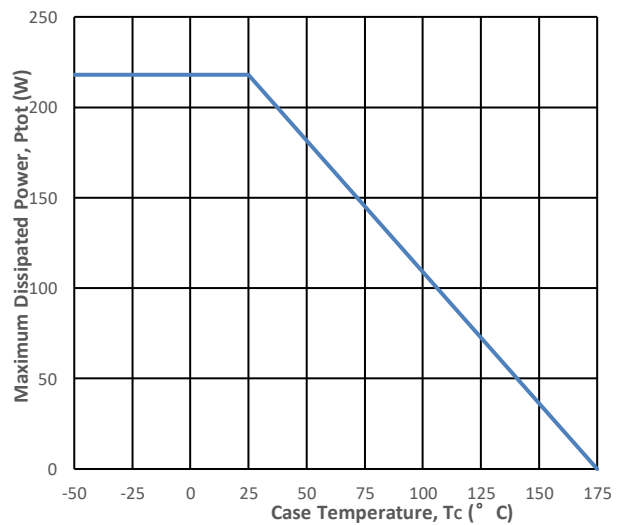
**Fig10. Output Capacitor Stored Energy**



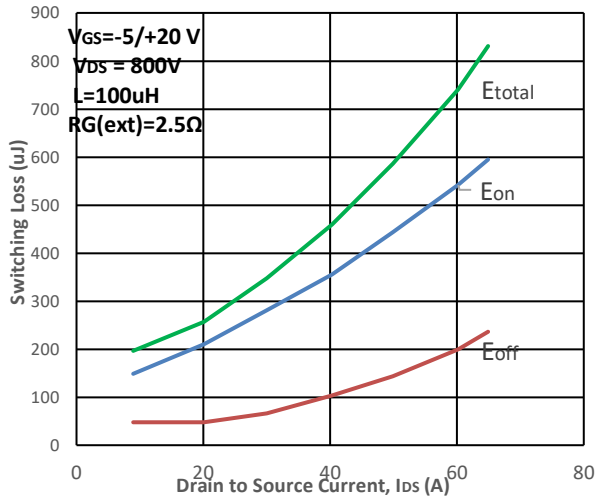
**Fig11. Capacitances vs. Drain-Source**



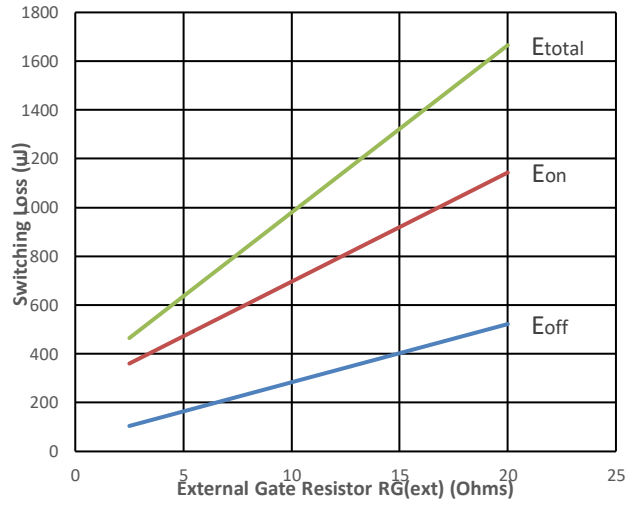
**Fig12. Max Power Dissipation Derating Vs Tc**



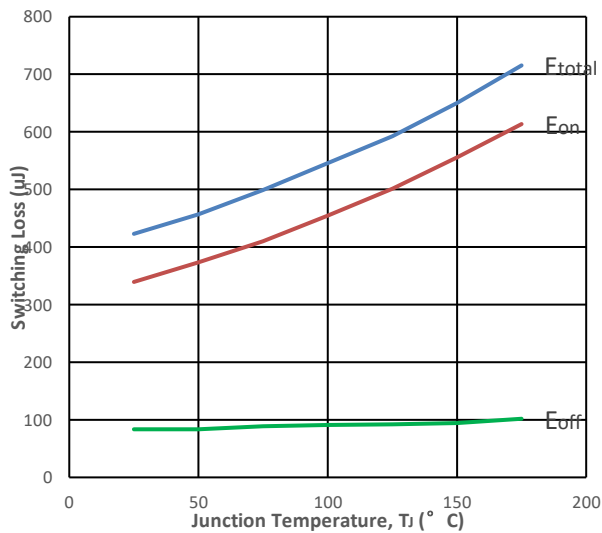
**Fig13. Switching Energy vs. Drain Current**



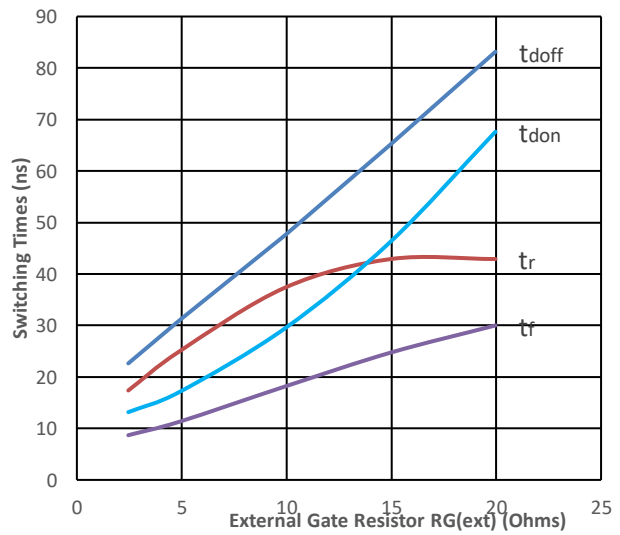
**Fig14. Switching Energy vs.  $R_{G(ext)}$**



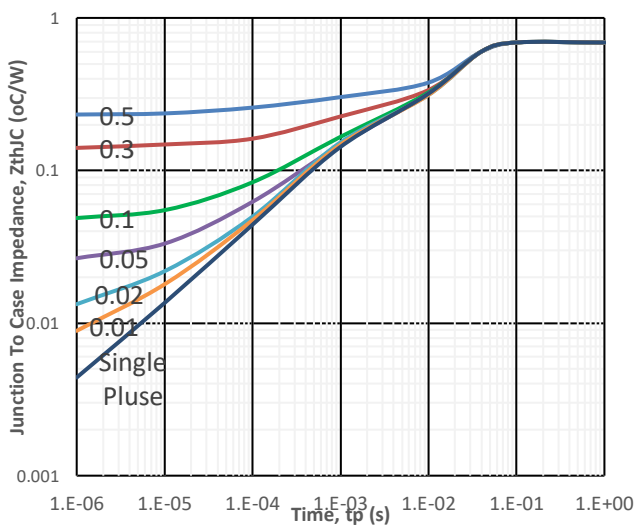
**Fig15. Switching Energy vs. Temperature**



**Fig16. Switching Times vs.  $R_{G(ext)}$**



**Fig17. Transient Thermal Impedance**



**Fig18. Safe Operating Area**

